

DESCRIPTION

Preliminary Specification

The NN518128 is a high performance CMOS Dynamic Random Access Memory organized as 131,072 words by 8 bits. The NN518128 is fabricated with advanced CMOS technology and designed with innovative design techniques resulting in high speed, extremely low power and wide operating margins at both component and system levels.

The NN518128 features a high speed page mode operation in which a high speed read, write or read-write is performed on any column address along a row address.

An extremely short row address capture time and an asynchronous column address decoder relax the timing constraints associated with address multiplexing.

The outputs are tri-stated by $\overline{\text{CAS}}$ which, in essence, acts as an output enable independent of $\overline{\text{RAS}}$ with very fast $\overline{\text{CAS}}$ to output access time.

Refresh is accomplished by performing $\overline{\text{RAS}}$ only refresh cycles, hidden refresh cycles, $\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ refresh cycles, or normal read or write cycles on the 512 address combinations of A0 to A8 during a 8 ms period.

Multiplexed address inputs permit the NN518128 to be packaged in a standard 26-pin plastic SOJ. The package sizes provide high system bit densities. System level features include single power supply of 5V ±10% tolerance and direct interface with high performance TTL logic families.

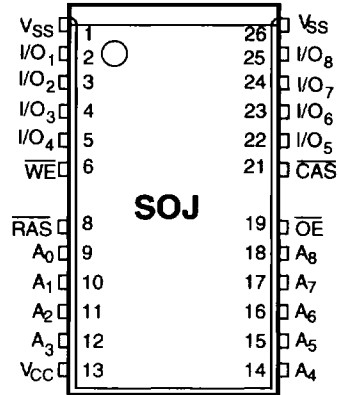
FEATURES

- 131,072 × 8 bit Organization
- Single 5V ±10% Power Supply
- Performance Ranges

| Parameter | -50 | -60 | -70 |
|---|------|-------|-------|
| Max. $\overline{\text{RAS}}$ Access Time (t_{RAC}) | 50ns | 60ns | 70ns |
| Max. $\overline{\text{CAS}}$ Access Time (t_{CAC}) | 15ns | 15ns | 20ns |
| Max. Column Address Access Time (t_{AA}) | 25ns | 30ns | 35ns |
| Min. Read/Write Cycle Time (t_{RC}) | 90ns | 110ns | 130ns |

- Fast Page Mode Operation
- Low Power Operation
 - Low Standby Current (CMOS level input)
 - Standard 1mA
 - L version 50µA
- 512 Refresh Cycles
 - Standard distributed across 8ms
 - L version distributed across 32ms
- Self Refresh Mode (L version)
- All inputs/Outputs and Clocks fully TTL and CMOS compatible
- Refresh Modes
 - $\overline{\text{RAS}}$ only
 - $\overline{\text{CAS}}$ before $\overline{\text{RAS}}$
 - Hidden Refresh
- High Reliability Packages
 - Plastic 26pin SOJ (P26SJ-2A2)

PIN CONFIGURATION

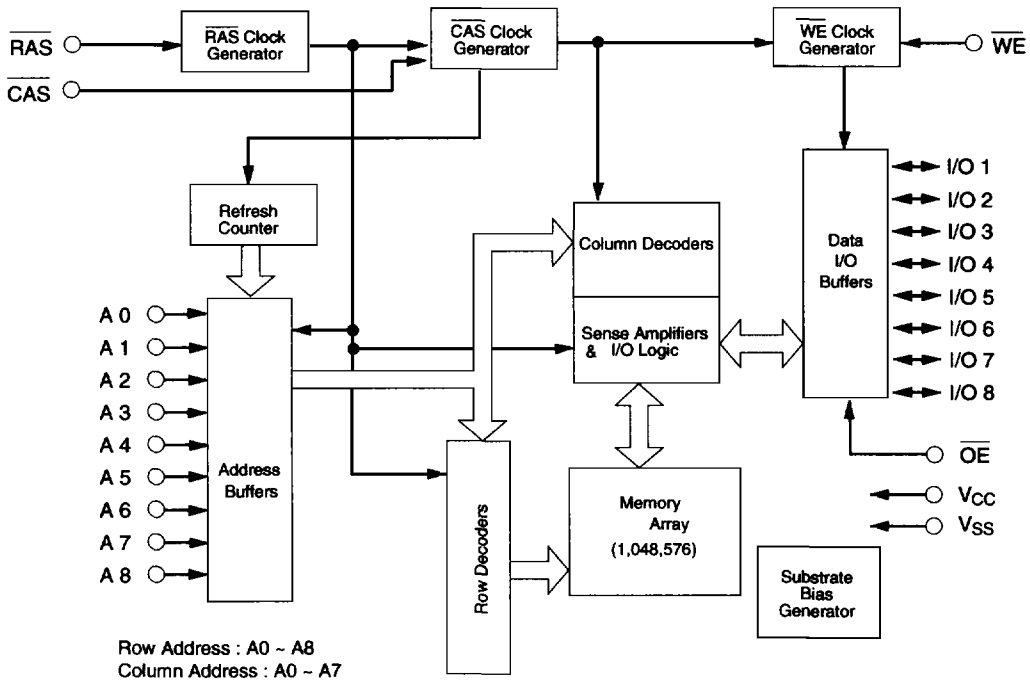


26-pin SOJ (300mil)
P26SJ-2A2

PIN NAMES

| | |
|-------------------------|-----------------------|
| A0~A8 | Address Inputs |
| $\overline{\text{RAS}}$ | Row Address Strobe |
| $\overline{\text{CAS}}$ | Column Address Strobe |
| $\overline{\text{OE}}$ | Output Enable |
| I/O1~I/O8 | Data-in / Data-out |
| $\overline{\text{WE}}$ | Write Enable |
| V _{CC} | +5V Supply |
| V _{SS} | Ground |
| NC | No Connection |

FUNCTIONAL BLOCK DIAGRAM



ABSOLUTE MAXIMUM RATINGS

| RATING | SYMBOL | VALUE | UNIT |
|--|-------------------|-------------|------|
| Voltage on Any Pin Relative to V_{SS} | V_{in}, V_{out} | -1 to 7 | V |
| Voltage on V_{CC} Relative to V_{SS} | V_{CC} | -1 to 7 | V |
| Storage Temperature (Plastic) | T_{stg} | -55 to +125 | °C |
| Power Dissipation | P_d | 1.0 | W |
| Ambient Operating Temperature | T_a | 0 to + 70 | °C |
| Short Circuit Output Current | I_{out} | 50 | mA |

Permanent device damage can occur if absolute maximum ratings are exceeded. Functional operation should be restricted to the conditions as detailed in the operational sections of this data sheet. Exposure to absolute maximum rating conditions for extended periods can affect device reliability.

DC OPERATING CONDITIONS

| SYMBOL | PARAMETER | MIN. | TYP. | MAX. | UNIT |
|----------|--------------------------------|------|------|------|------|
| V_{CC} | Supply Voltage | 4.5 | 5.0 | 5.5 | V |
| V_{SS} | Supply Voltage | 0 | 0 | 0 | V |
| V_{IH} | Input High Voltage, All Inputs | 2.4 | — | 6.5 | V |
| V_{IL} | Input Low Voltage, All Inputs | -1.0 | — | 0.8 | V |

Note: All voltage values in this data sheet are with respect to V_{SS} unless otherwise specified.

DC ELECTRICAL CHARACTERISTICS (0°C ≤ Ta ≤ 70°C, V_{CC} = 5.0V ±10%)

| SYMBOL | PARAMETER | SPEED | MIN. | MAX. | UNIT | TEST CONDITIONS | NOTES |
|------------------|--|-------|------|------|------|--|-------|
| I _{CC1} | Operating Current | -50 | | 100 | mA | t _{RC} = t _{RC} (min.) RAS, CAS, Address cycling | 1, 2 |
| | | -60 | | 90 | mA | | |
| | | -70 | | 80 | mA | | |
| I _{CC2} | Standby Current | | | 1.0 | mA | RAS = CAS ≥ (V _{CC} - 0.2V) | |
| | | | | 2.0 | mA | RAS = CAS ≥ V _{IH} | |
| | Standby Current (L version) | | | 50 | μA | RAS = CAS ≥ (V _{CC} - 0.2V) All other inputs are stable at (V _{CC} - 0.2V) or (V _{SS} + 0.2V) | |
| I _{CC3} | Refresh Current (RAS only refresh) | -50 | | 100 | mA | t _{RC} = t _{RC} (min.) RAS cycling, CAS = V _{IH} | 1 |
| | | -60 | | 90 | mA | | |
| | | -70 | | 80 | mA | | |
| I _{CC4} | Fast Page Mode Current | -50 | | 70 | mA | t _{PC} = t _{PC} (min.) RAS = V _{IL} CAS, Address cycling | 1, 2 |
| | | -60 | | 60 | mA | | |
| | | -70 | | 50 | mA | | |
| I _{CC5} | Refresh Current (CAS before RAS refresh) | -50 | | 100 | mA | t _{RC} = t _{RC} (min.) RAS, CAS cycling | 1 |
| | | -60 | | 90 | mA | | |
| | | -70 | | 80 | mA | | |
| I _{CC6} | Refresh Current (L version : CAS before RAS refresh) | | | 150 | μA | 512 cycles / 32ms t _{RAS} ≤ 200ns, WE ≥ (V _{CC} - 0.2V) All other inputs are stable at (V _{CC} - 0.2V) or (V _{SS} + 0.2V) | |
| I _{CC7} | Self Refresh Mode Current (L version) | | | 100 | μA | RAS = CAS ≤ (V _{SS} + 0.2V) All other inputs high levels are (V _{CC} - 0.2V) or input low levels are (V _{SS} + 0.2V) | |
| I _{L1} | Input Leakage Current (Any input pin) | | -10 | 10 | μA | 0V ≤ V _{IH} ≤ 5.5V, Others = 0V | |
| I _{L0} | Output Leakage Current (For high impedance state) | | -10 | 10 | μA | RAS ≥ V _{IH} (min.), CAS ≥ V _{IH} (min.) 0V ≤ V _{OUT} ≤ 5.5V | |
| V _{OH} | Output High Voltage | | 2.4 | | V | I _{OH} = -5.0 mA | |
| V _{OL} | Output Low Voltage | | | 0.4 | V | I _{OL} = 4.2 mA | |

- Notes: 1. I_{CC1}, I_{CC3}, I_{CC4} and I_{CC5} depend on cycle rate.
2. I_{CC1} and I_{CC4} depend on output loading. Specified values are obtained with the outputs open.

CAPACITANCE (0°C ≤ Ta ≤ 70°C, V_{CC} = 5.0V ±10%, f = 1MHz)

| SYMBOL | PARAMETER | MIN. | MAX. | UNIT |
|------------------|------------------|------|------|------|
| C _{IN1} | Address(A0 - A8) | — | 5 | pF |
| C _{IN2} | RAS, CAS, WE, OE | — | 5 | pF |
| C _{OUT} | I/O1 ~ I/O8 | — | 7 | pF |

A.C. OPERATING CONDITIONS (0 °C ≤ Ta ≤ 70°C, V_{CC} = 5 V ± 10%, V_{SS} = 0 V) (NOTES 3, 4, 5)

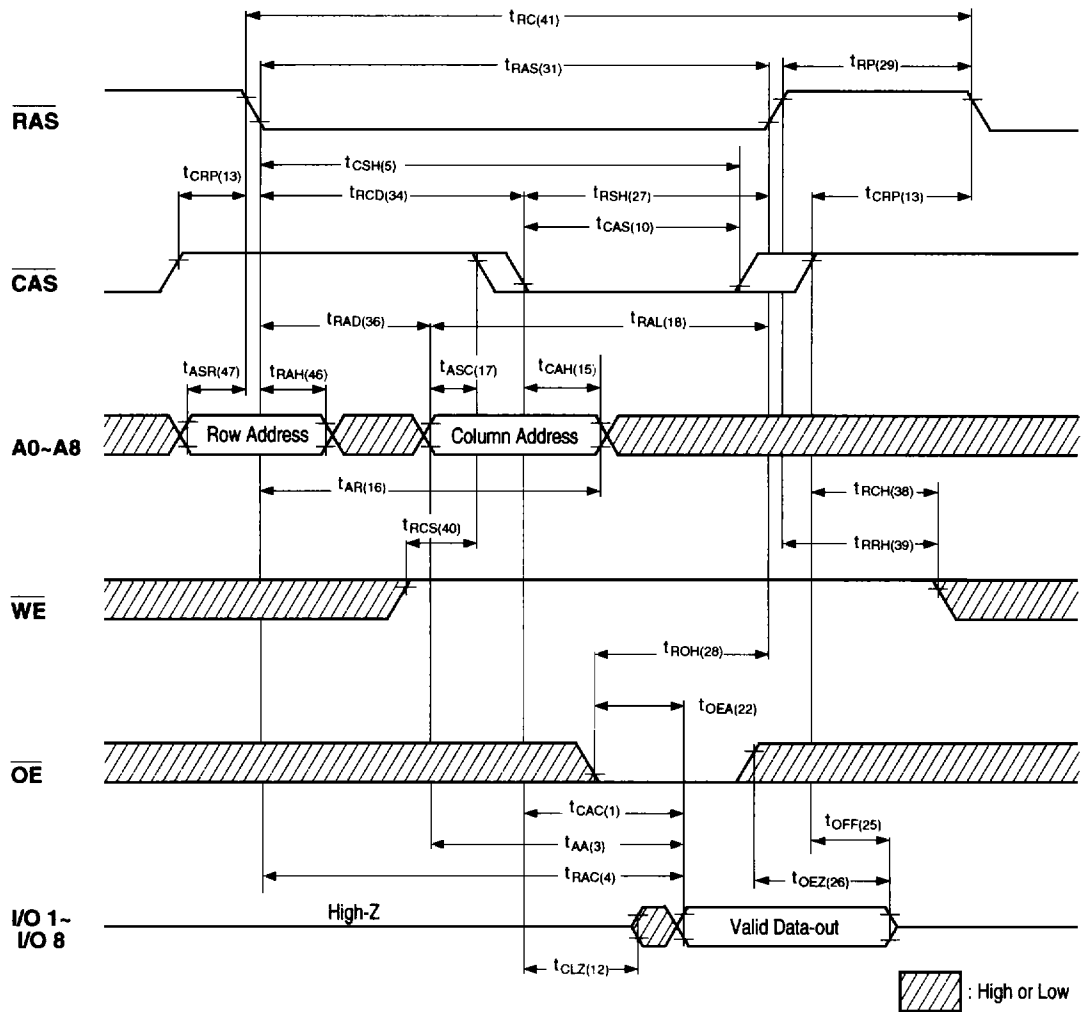
| NO. | SYMBOL | | PARAMETER | -50 | | -60 | | -70 | | UNIT | NOTE |
|-----|--|-------------------|--|------|------|------|------|------|------|------|-------|
| | JEDEC | STD | | MIN. | MAX. | MIN. | MAX. | MIN. | MAX. | | |
| 1 | t _{CL1QV} | t _{CAC} | Access Time from $\overline{\text{CAS}}$ | — | 15 | — | 15 | — | 20 | ns | 6,13 |
| 2 | t _{CH2QV} | t _{CPA} | Access Time from $\overline{\text{CAS}}$ Precharge | — | 30 | — | 35 | — | 40 | ns | 13,14 |
| 3 | t _{AVQV} | t _{AA} | Access Time from Column Address | — | 25 | — | 30 | — | 35 | ns | 7,13 |
| 4 | t _{RL1QV} | t _{RAC} | Access Time from $\overline{\text{RAS}}$ | — | 50 | — | 60 | — | 70 | ns | 6,7 |
| 5 | t _{RL1CH1} | t _{CSH} | $\overline{\text{CAS}}$ Hold Time | 50 | — | 60 | — | 70 | — | ns | |
| 6 | t _{RL1CH1} | t _{CHR} | $\overline{\text{CAS}}$ Hold Time ($\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ Refresh) | 10 | — | 10 | — | 10 | — | ns | |
| 7 | t _{RL1CX} | t _{CHS} | $\overline{\text{CAS}}$ Precharge Time (Self Refresh Mode) | -50 | — | -50 | — | -50 | — | ns | |
| 8 | t _{CH2CL2} | t _{CPN} | $\overline{\text{CAS}}$ Precharge Time ($\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ Refresh) | 10 | — | 10 | — | 10 | — | ns | |
| 9 | t _{CH2CL2} | t _{CP} | $\overline{\text{CAS}}$ Precharge Time (Fast Page Mode) | 5 | — | 5 | — | 5 | — | ns | 14 |
| 10 | t _{CL1CH1} | t _{CAS} | $\overline{\text{CAS}}$ Pulse Width | 15 | 100K | 15 | 100K | 20 | 100K | ns | |
| 11 | t _{CL1RL2} | t _{CSR} | $\overline{\text{CAS}}$ Setup Time ($\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ Refresh) | 5 | — | 5 | — | 5 | — | ns | |
| 12 | t _{CL1QX} | t _{CLZ} | $\overline{\text{CAS}}$ to Output in Low-Z | 0 | — | 0 | — | 0 | — | ns | 8 |
| 13 | t _{CH2RL2} | t _{CRP} | $\overline{\text{CAS}}$ to $\overline{\text{RAS}}$ Precharge Time | 5 | — | 5 | — | 5 | — | ns | |
| 14 | t _{CL1WL2} | t _{CWD} | $\overline{\text{CAS}}$ to $\overline{\text{WE}}$ Delay Time | 45 | — | 45 | — | 50 | — | ns | 11 |
| 15 | t _{CL1AX} | t _{CAH} | Column Address Hold Time | 10 | — | 15 | — | 15 | — | ns | |
| 16 | t _{RL1AX} | t _{AR} | Column Address Hold Time Referenced to $\overline{\text{RAS}}$ | 35 | — | 40 | — | 40 | — | ns | |
| 17 | t _{AVCL2} | t _{ASC} | Column Address Setup Time | 0 | — | 0 | — | 0 | — | ns | 14 |
| 18 | t _{AVRH1} | t _{RAL} | Column Address to $\overline{\text{RAS}}$ Lead Time | 27 | — | 30 | — | 35 | — | ns | |
| 19 | t _{AVWL2} | t _{AWD} | Column Address to $\overline{\text{WE}}$ Delay Time | 57 | — | 60 | — | 65 | — | ns | 11 |
| 20 | t _{CL1DX} t _{WL1DX} | t _{DH} | Data Hold Time | 10 | — | 10 | — | 15 | — | ns | 12 |
| 21 | t _{DVCL2} t _{DVWL2} | t _{DS} | Data Setup Time | 0 | — | 0 | — | 0 | — | ns | 12 |
| 22 | t _{OL1QV} | t _{OEa} | $\overline{\text{OE}}$ Access Time | — | 15 | — | 15 | — | 20 | ns | |
| 23 | t _{WL1OL2} | t _{OEh} | $\overline{\text{OE}}$ Command Hold Time | 15 | — | 15 | — | 20 | — | ns | |
| 24 | t _{CH2QV} | t _{OEd} | $\overline{\text{OE}}$ to Data Delay Time | 10 | — | 10 | — | 10 | — | ns | |
| 25 | t _{CH2OZ} | t _{OFF} | Output Buffer Turn-off Delay Time | 0 | 13 | 0 | 15 | 0 | 20 | ns | 10 |
| 26 | t _{CH2QX} | t _{OEz} | Output Buffer Turn-off Delay Time Referenced to $\overline{\text{OE}}$ | 0 | 10 | 0 | 15 | 0 | 15 | ns | |
| 27 | t _{CL1RH1} | t _{RSH} | $\overline{\text{RAS}}$ Hold Time | 15 | — | 15 | — | 20 | — | ns | |
| 28 | t _{OL1RH1} | t _{ROH} | $\overline{\text{RAS}}$ Hold Time Referenced to $\overline{\text{OE}}$ | 10 | — | 10 | — | 10 | — | ns | |
| 29 | t _{RH2RL2} | t _{RP} | $\overline{\text{RAS}}$ Precharge Time | 25 | — | 30 | — | 40 | — | ns | |
| 30 | t _{RH2RL2} | t _{RPS} | $\overline{\text{RAS}}$ Precharge Time (Self Refresh Mode) | 90 | — | 110 | — | 130 | — | ns | |
| 31 | t _{RL1RH1} | t _{RAS} | $\overline{\text{RAS}}$ Pulse Width | 50 | 100K | 60 | 100K | 70 | 100K | ns | |
| 32 | t _{RL1RH1} | t _{RASP} | $\overline{\text{RAS}}$ Pulse Width (Fast Page Mode) | 50 | 100K | 60 | 100K | 70 | 100K | ns | |
| 33 | t _{RL1RH1} | t _{RASS} | $\overline{\text{RAS}}$ Pulse Width (Self Refresh Mode) | 300 | — | 300 | — | 300 | — | μs | |
| 34 | t _{RL1CL1} | t _{RCD} | $\overline{\text{RAS}}$ to $\overline{\text{CAS}}$ Delay Time | 13 | 35 | 13 | 45 | 13 | 50 | ns | 6 |
| 35 | t _{RH2CL2} | t _{RPC} | $\overline{\text{RAS}}$ to $\overline{\text{CAS}}$ Precharge Time | 10 | — | 10 | — | 10 | — | ns | |
| 36 | t _{RL1AV} | t _{RAD} | $\overline{\text{RAS}}$ to Column Address Delay Time | 11 | 23 | 11 | 30 | 11 | 35 | ns | 7 |
| 37 | t _{RL1WL2} | t _{RWD} | $\overline{\text{RAS}}$ to $\overline{\text{WE}}$ Delay Time | 80 | — | 90 | — | 100 | — | ns | 11 |
| 38 | t _{CH2WL2} | t _{RCH} | Read Command Hold Time | 0 | — | 0 | — | 0 | — | ns | 9 |
| 39 | t _{RH2WL2} | t _{RRH} | Read Command Hold Time Referenced to $\overline{\text{RAS}}$ | 10 | — | 10 | — | 10 | — | ns | 9 |

| NO. | SYMBOL | | PARAMETER | -50 | | -60 | | -70 | | UNIT | NOTE |
|-----|--------------|------------|---|------|------|------|------|------|------|------|-------|
| | JEDEC | STD | | MIN. | MAX. | MIN. | MAX. | MIN. | MAX. | | |
| 40 | t_{WH2CL2} | t_{RCS} | Read Command Setup Time | 0 | — | 0 | — | 0 | — | ns | 9 |
| 41 | t_{RL2RL2} | t_{RC} | Random Read or Write Cycle Time | 90 | — | 110 | — | 130 | — | ns | |
| 42 | t_{CL2CL2} | t_{PC} | Read or Write Cycle Time (Fast Page Mode) | 33 | — | 40 | — | 45 | — | ns | 13,14 |
| 43 | t_{RL2RL2} | t_{RMW} | Read-Modify-Write Cycle Time | 145 | — | 165 | — | 185 | — | ns | |
| 44 | t_{CL2CL2} | t_{PRMW} | Read-Modify-Write Cycle Time (Fast Page Mode) | 90 | — | 95 | — | 100 | — | ns | 13,14 |
| 45 | t_{REF} | t_{REF} | Refresh Period | — | 8 | — | 8 | — | 8 | ms | 15 |
| 46 | t_{RL1AX} | t_{RAH} | Row Address Hold Time | 8 | — | 8 | — | 8 | — | ns | |
| 47 | t_{AVRL2} | t_{ASR} | Row Address Setup Time | 0 | — | 0 | — | 0 | — | ns | |
| 48 | t_T | t_T | Transition Time (Rise and Fall) | 2 | 50 | 2 | 50 | 2 | 50 | ns | 4,5 |
| 49 | t_{CL1WH1} | t_{WCH} | Write Command Hold Time | 10 | — | 10 | — | 15 | — | ns | |
| 50 | t_{WL1WH1} | t_{WCP} | Write Command Pulse Width | 10 | — | 10 | — | 15 | — | ns | |
| 51 | t_{WL1CL2} | t_{WCS} | Write Command Setup Time | 0 | — | 0 | — | 0 | — | ns | 11 |
| 52 | t_{WL1CH1} | t_{CWL} | Write Command to \overline{CAS} Lead Time | 15 | — | 15 | — | 20 | — | ns | |
| 53 | t_{WL1RH1} | t_{RWL} | Write Command to \overline{RAS} Lead Time | 15 | — | 15 | — | 20 | — | ns | |

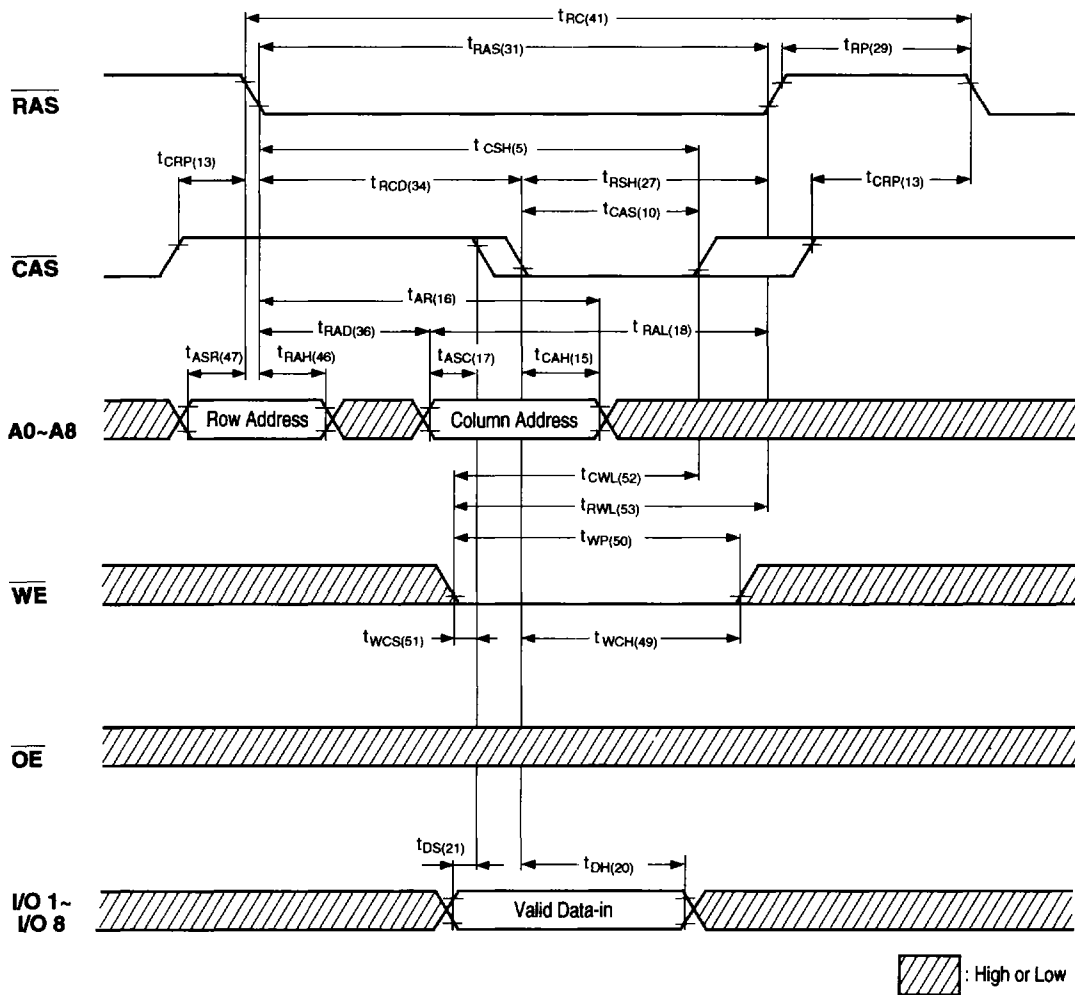
Notes:

- Eight Initialization Cycles are required following a 200 μ s pause after Power Up. These Initialization Cycles may consist of any combination of the following : \overline{RAS} only refresh Cycles, Read Cycles, Write Cycles, \overline{CAS} before \overline{RAS} refresh Cycles.
- AC measurements assume $t_T=3$ ns. All AC parameters are measured with $V_{IL}(\text{min.}) \geq V_{SS}$ and $V_{IH}(\text{max.}) \leq V_{CC}$ and with a load equivalent to two TTL loads and 50pF.
- $V_{IH}(\text{min.})$ and $V_{IL}(\text{max.})$ are reference levels for measuring timing of input signals. Also, transition times are measured between V_{IH} and V_{IL} .
- Operation within the $t_{RCD}(\text{max.})$ limit ensures that $t_{RAC}(\text{max.})$ can be met. $t_{RCD}(\text{max.})$ is specified as a reference point only. If t_{RCD} is greater than the specified $t_{RCD}(\text{max.})$ limit, then access time is controlled by t_{CAC} .
- Operation within the $t_{RAD}(\text{max.})$ limit ensures that $t_{RAC}(\text{max.})$ can be met. $t_{RAD}(\text{max.})$ is specified as a reference point only. If t_{RAD} is greater than the specified $t_{RAD}(\text{max.})$ limit, then access time is controlled by t_{AA} .
- Assumes three state test load (5pF and a 220 ohm to 1.3V Thevenin equivalent).
- Either t_{RCH} or t_{RRH} must be satisfied for a read cycle.
- $t_{OFF}(\text{max.})$ defines the time at which the output achieves an open circuit condition and is not referenced to output voltage levels.
- t_{WCS} , t_{RWD} , t_{CWD} and t_{AWD} are not restrictive operating parameters. They are included in the data sheet as electrical characteristics only. If $t_{WCS} \geq t_{WCS}(\text{min.})$, the cycle is an early write cycle and data-out pins will remain open circuit (high impedance) throughout the entire cycle. If $t_{RWD} \geq t_{RWD}(\text{min.})$, $t_{CWD} \geq t_{CWD}(\text{min.})$ and $t_{AWD} \geq t_{AWD}(\text{min.})$, the cycle is a read-modify-write cycle and the data-out will contain data read from the selected cell. If neither of the above conditions is satisfied, the condition of the data-out (at access time) is indeterminate.
- These parameters are referenced to \overline{CAS} leading edge in early write cycles and to \overline{WE} leading edge in read-modify-write cycles.
- Access time is determined by the longer of t_{AA} , t_{CAC} , or t_{CPA} .
- $t_{ASC} \geq t_{CP}$ to achieve $t_{PC}(\text{min.})$ and $t_{CPA}(\text{max.})$ values.
- $t_{REF}=32$ msec for Long Refresh version (L version)

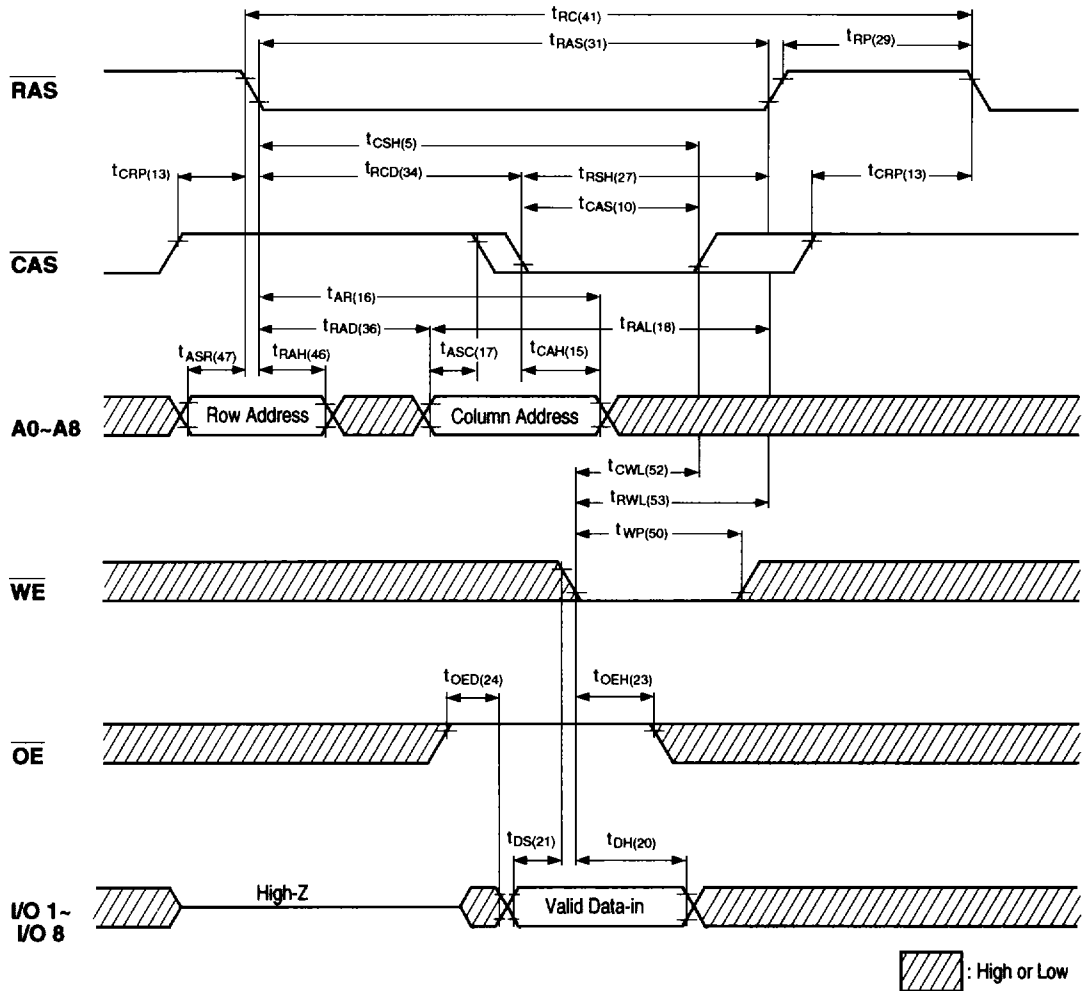
READ CYCLE



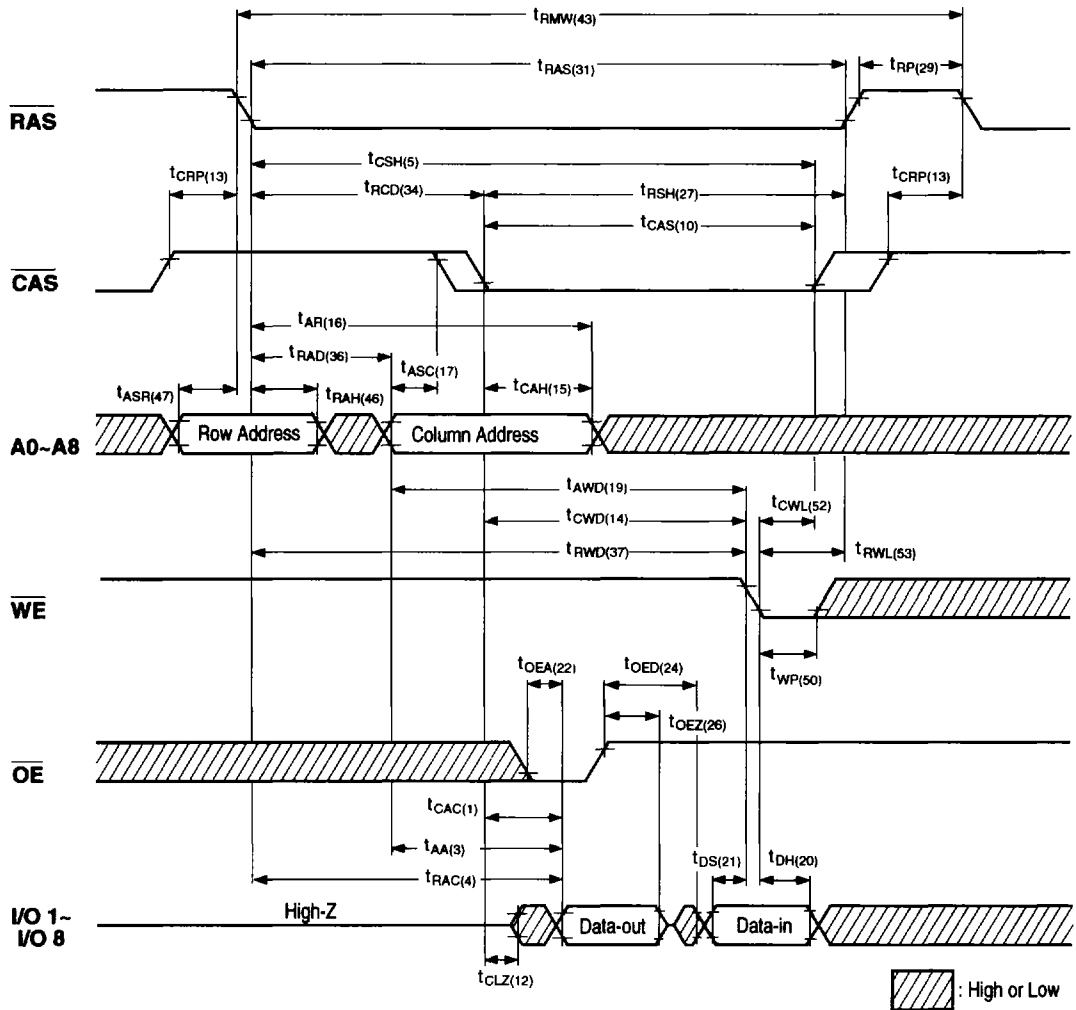
WRITE CYCLE (EARLY WRITE)



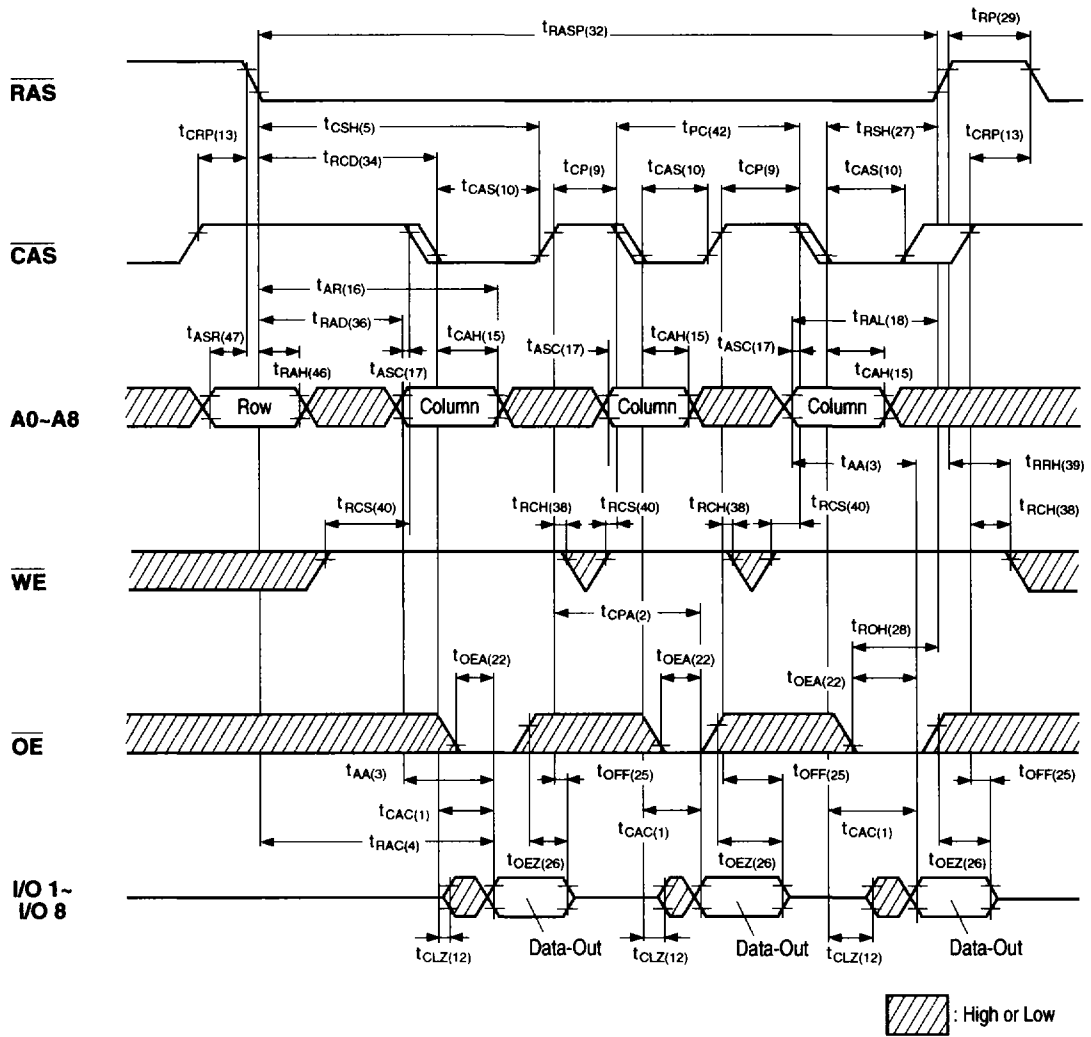
WRITE CYCLE (OE-CONTROLLED WRITE)



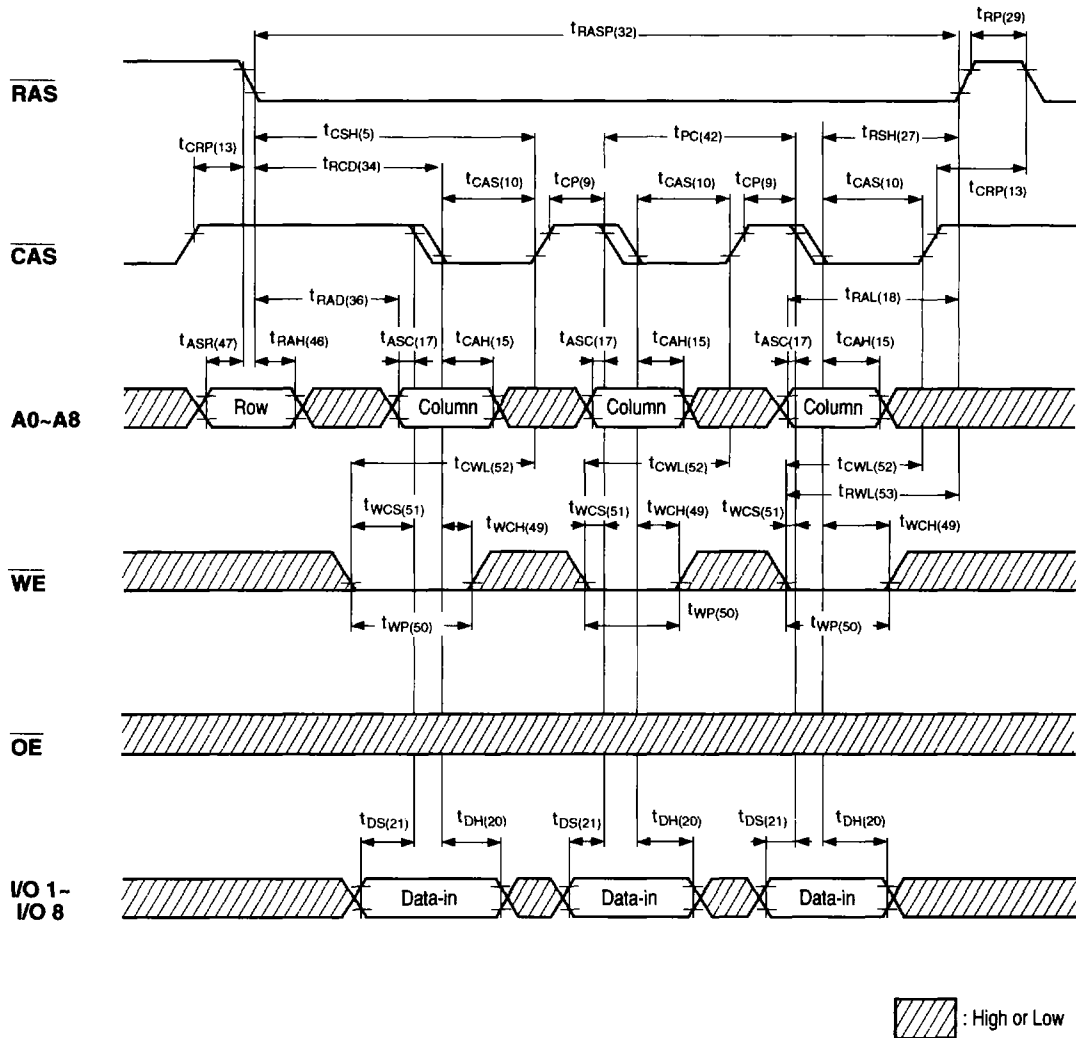
READ-MODIFY-WRITE CYCLE



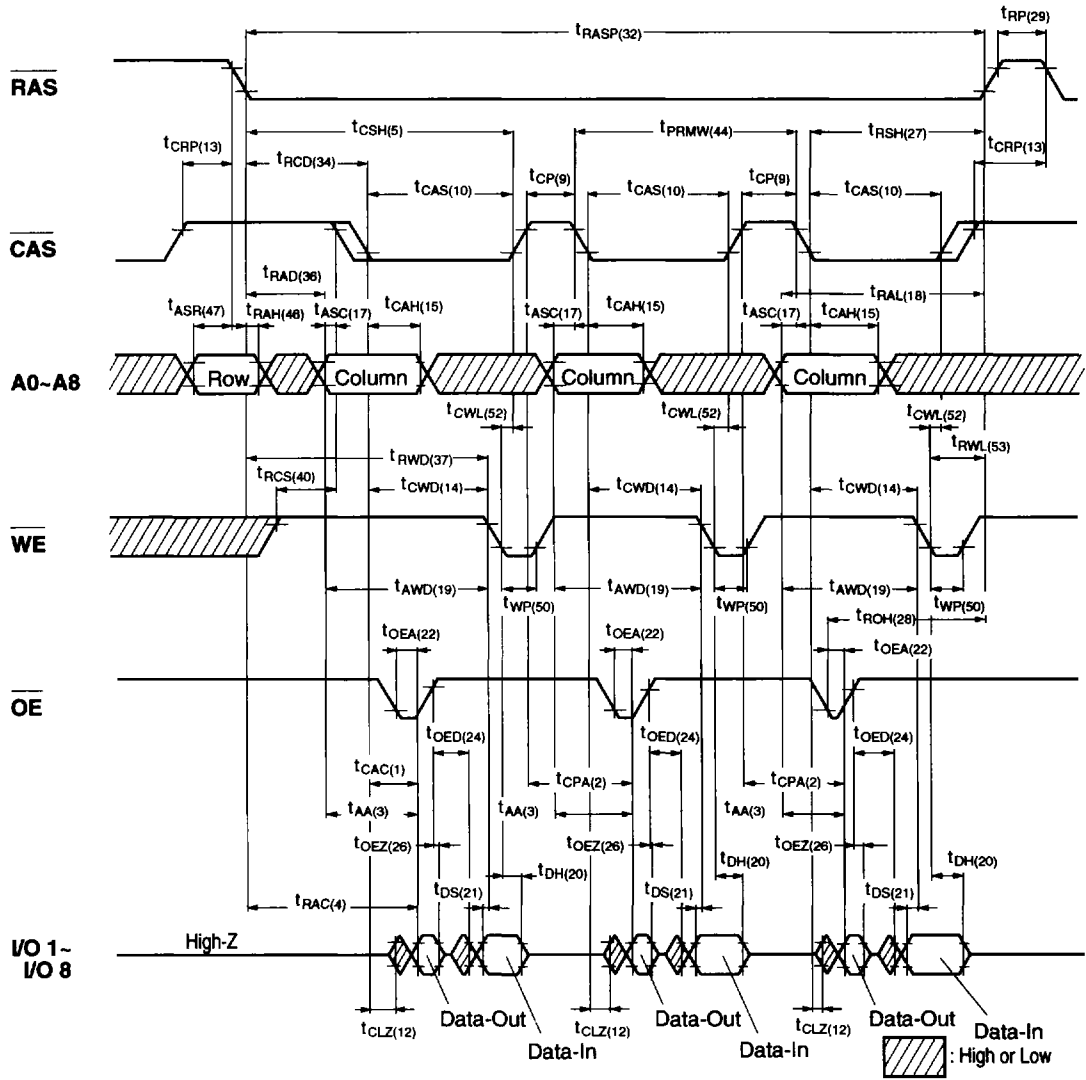
FAST PAGE MODE READ CYCLE



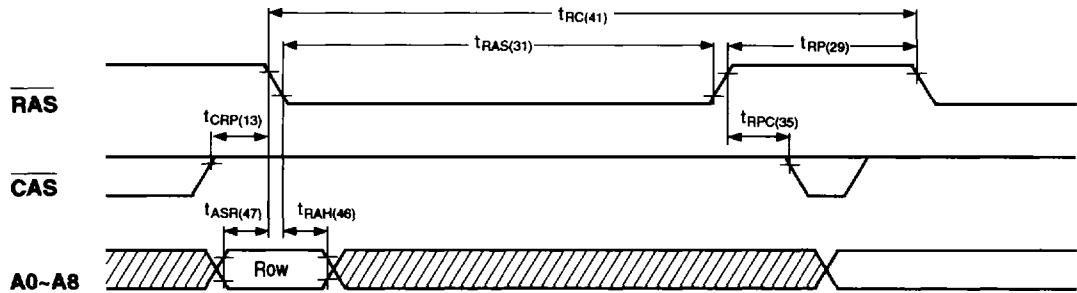
FAST PAGE MODE EARLY WRITE CYCLE



FAST PAGE MODE READ-MODIFY-WRITE CYCLE



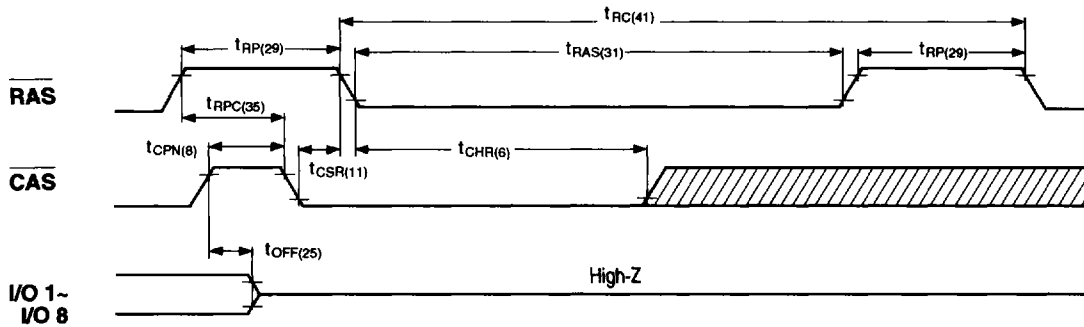
RAS ONLY REFRESH CYCLE



Note: \overline{WE} , \overline{OE} = Don't care.

 : High or Low

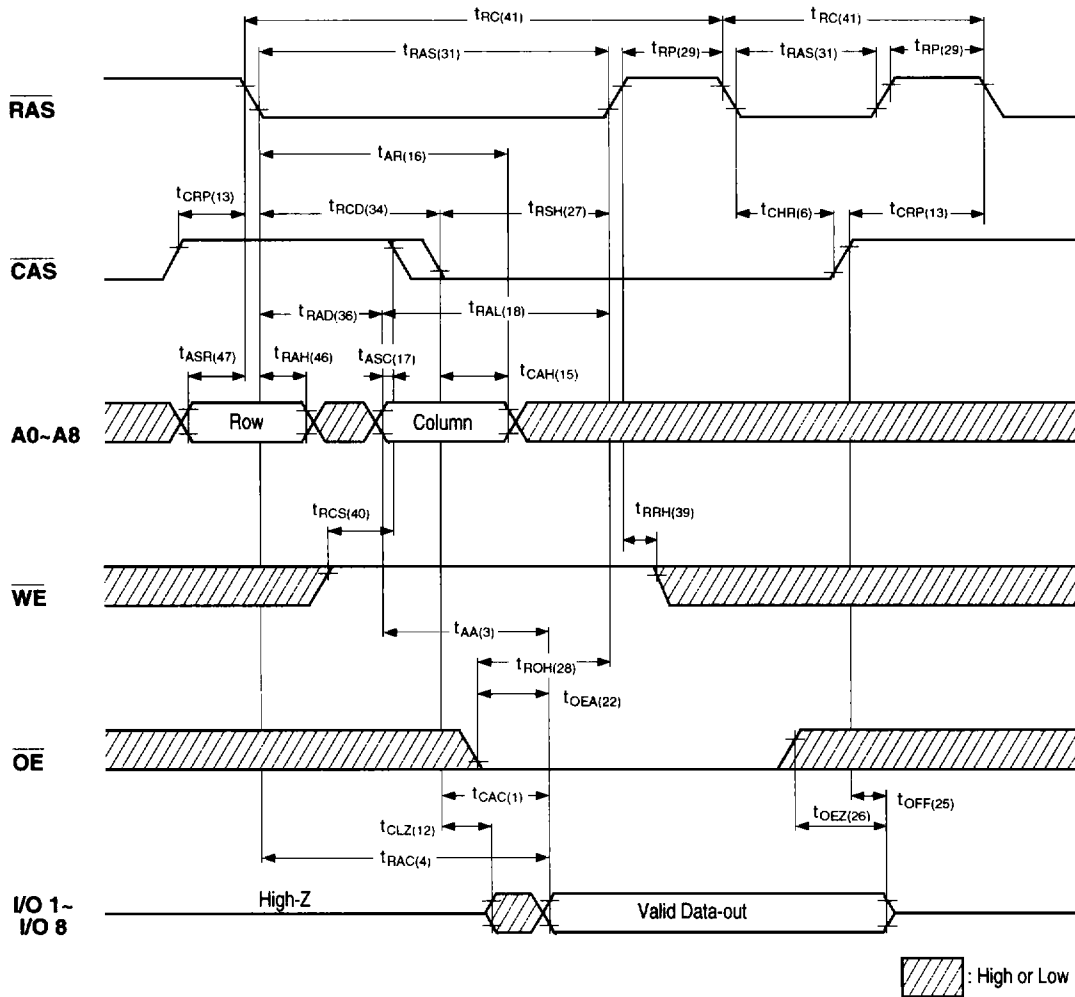
CAS BEFORE RAS REFRESH CYCLE



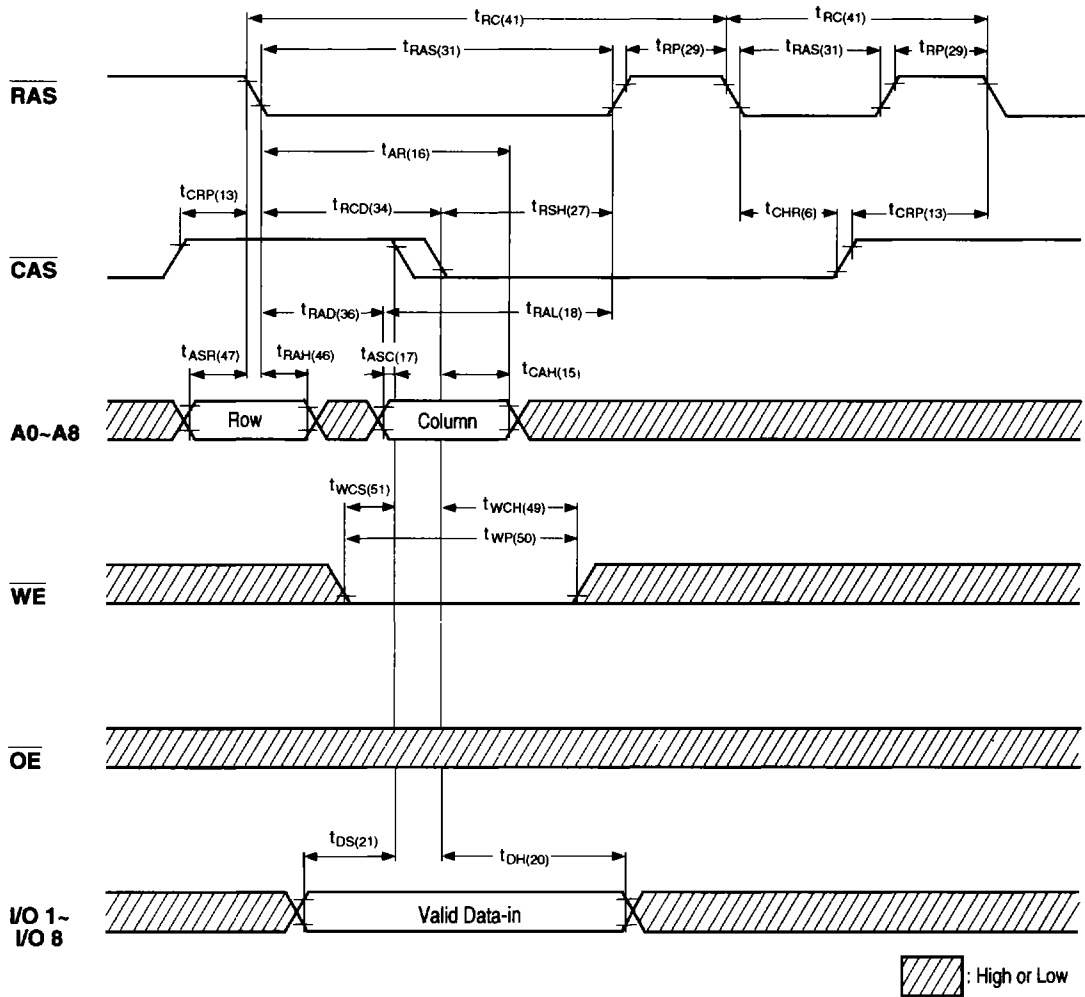
Note: \overline{WE} , \overline{OE} , A0~A8 = Don't care.

 : High or Low

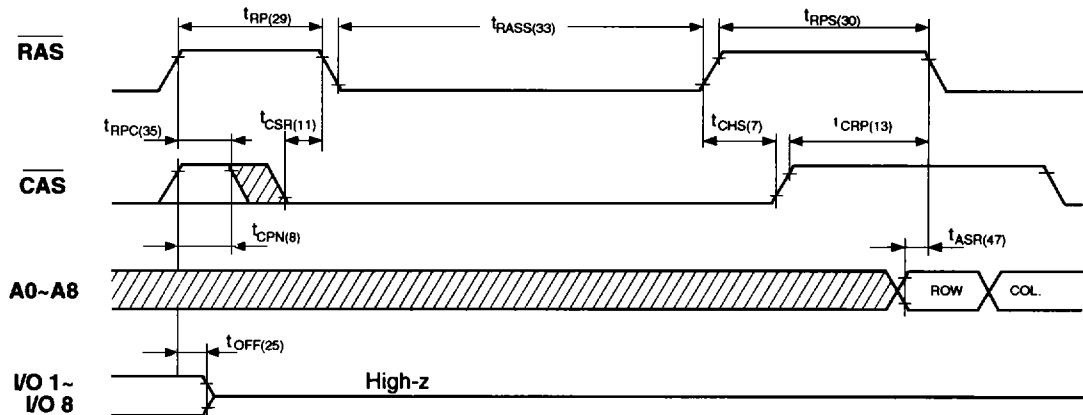
HIDDEN REFRESH CYCLE (READ)



HIDDEN REFRESH CYCLE (EARLY WRITE)



SELF REFRESH MODE



 : High or Low

■ The NN518128L has a Self Refresh Mode.

a. Entering the Self Refresh Mode:

The NN518128L Self Refresh Mode is entered by using $\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ cycle and holding $\overline{\text{RAS}}$ and $\overline{\text{CAS}}$ signal " low " longer than 300 μs .

b. Continuing the Self Refresh Mode:

The Self Refresh Mode is continued by holding $\overline{\text{RAS}}$ " low " after entering the Self Refresh Mode. It does not depend on being $\overline{\text{CAS}}$ " high " or " low " after entering the Self Refresh Mode to continue the Self Refresh Mode.

c. Exiting the Self Refresh Mode:

The NN518128L exits the Self Refresh Mode when the $\overline{\text{RAS}}$ signal is brought " high ".

ORDERING INFORMATION

NN518128XJ - XX

| | |
|----------------|--|
| <u>SPEED</u> | 50 : 50ns 60 : 60ns 70 : 70ns |
| <u>PACKAGE</u> | J : Plastic SOJ |
| <u>VERSION</u> | BLANK : Standard Version L : Long Refresh Version 32ms Refresh |
| <u>MODE</u> | 8128 : Fast Page 128K x 8 512 refresh Cycle |